

Notice of References Cited	Application/Control No. 10/763,728	Applicant(s)/Patent Under Reexamination BERWALD ET AL.	
	Examiner A. Dexter Tugbang	Art Unit 3729	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-RE28,559	09-1975	Villano, John A.	409/131 x
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	You et al., "Effect of Milling Process on the Magnetic Properties of FIB Patterned Magnetic Nanostructures", Digest of Technical Properties, International Magnetics Conference 2002, page EU7, April 28, 2002.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.